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REV. 9-88U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

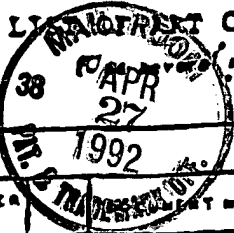
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LITERATURE CITED BY APPLICANT



(include if necessary)

APPLICANT

GRIFFITH ET AL

FILING DATE

July 15, 1991

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA						
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL							
AM							
AN							
AO							
AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

QEA	AR	Chiba, N., et al., <u>Int. Arch. Allergy Appl. Immunol.</u> 93: 83-88 (1990).
QEA	AS	Ishizaki, T., et al., <u>Ann. Allergy.</u> 58: 265-270. (1987).
QEA	AT	Ito, Y., et al., <u>Int. Arch. Allergy Appl. Immunol.</u> 81: 174-179 (1986).

EXAMINER

DATE CONSIDERED

6/30/92

U.S. PATENT DOCUMENTS

[illegible]

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

DEA	AU	Matsushita, S., <u>et al.</u> , <u>J. Immunol.</u> <u>138</u> : 109-115. (1987)
DEA	AV	Miyazawa, H., <u>et al.</u> , <u>J. Allergy Clin. Immunol.</u> <u>82</u> : 407-413. (1989)
DEA	AW	Panzani, R., <u>et al.</u> , <u>Ann. Allergy</u> <u>57</u> : 26-30. (1986)
DEA	AX	Sakaguchi, M., <u>et al.</u> , <u>Allergy</u> <u>45</u> : 309-312. (1990)
DEA	AY	Tamura, S., <u>et al.</u> , <u>Microbiol. Immunol.</u> <u>30</u> : 883-891. (1986)
DEA	AZ	Taniai, M., <u>et al.</u> , <u>FEBS Lett.</u> <u>239</u> : 329-332. (1988)

Examiner

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not

U.S. PATENT DOCUMENTS

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner

Date Considered	Amount	Particulars
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